ISO/TR 12489: Reliability modelling & calculation of safety systems. Presentation and applications

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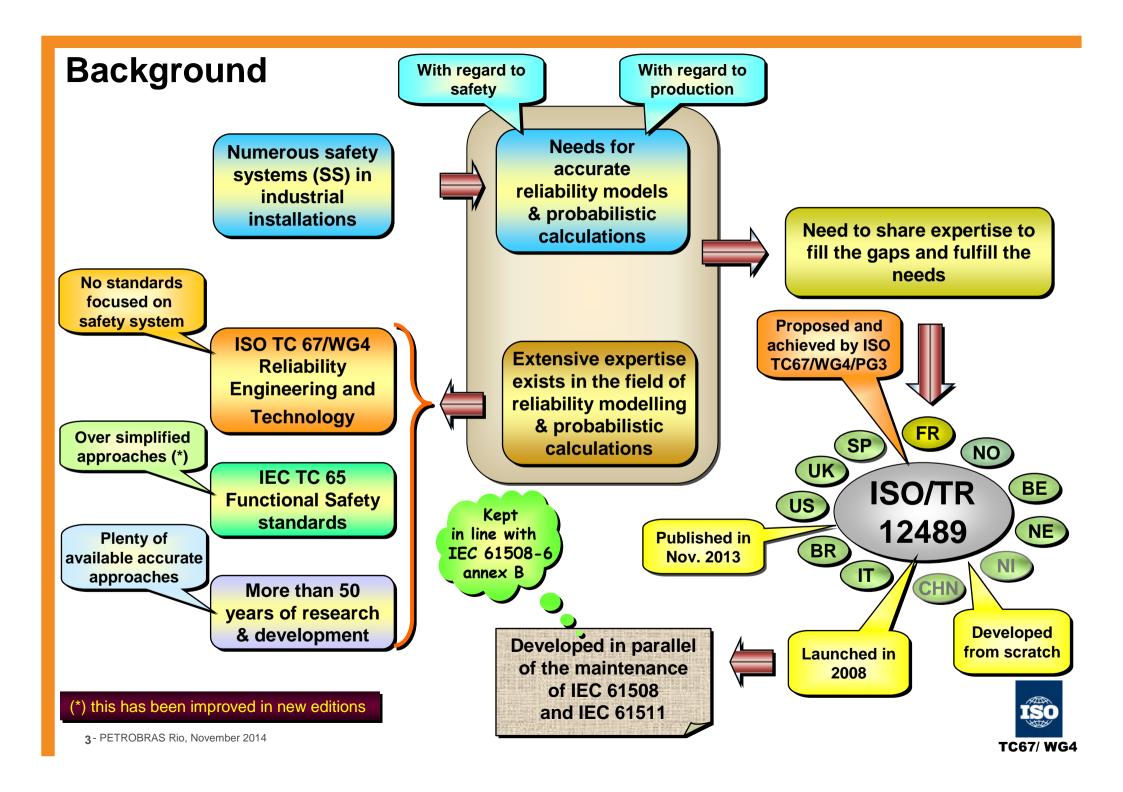
Presentation of ISO/TR 12489

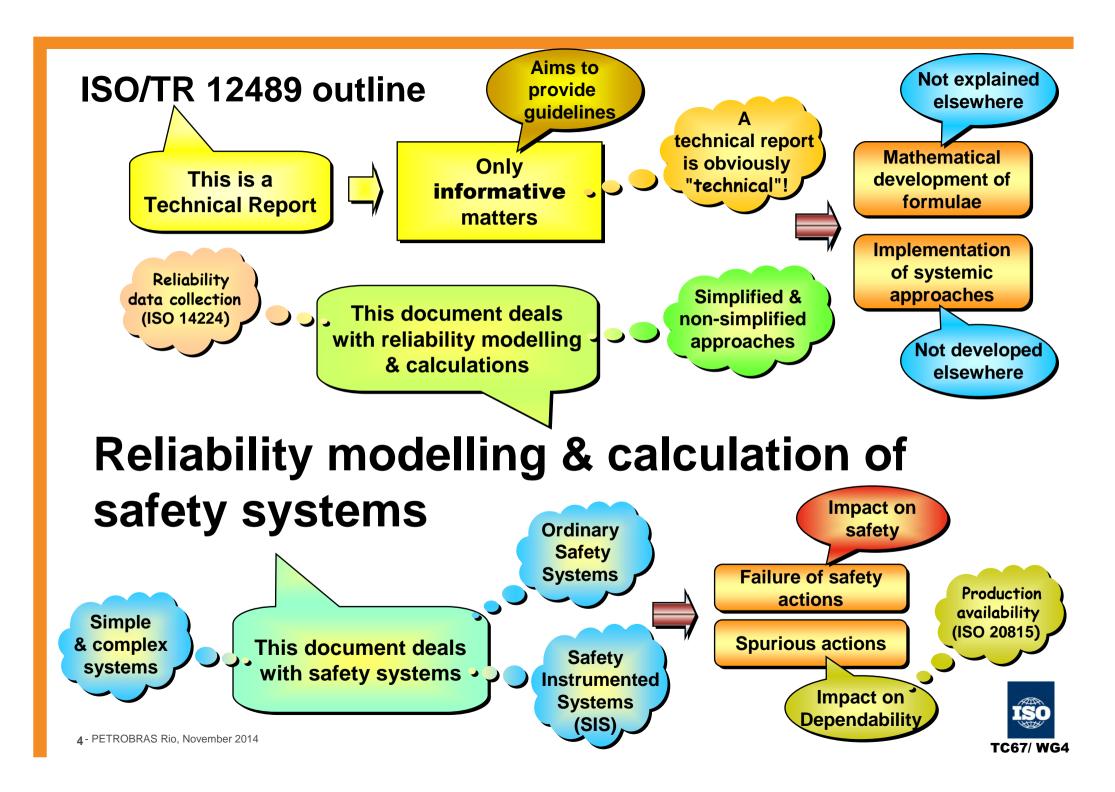
TR prepared by ISO TC67 WG4/Project Group 3

PG3 leader : Jean Pierre Signoret (Total)

WG4 Convenor: Runar Østebø (Statoil)





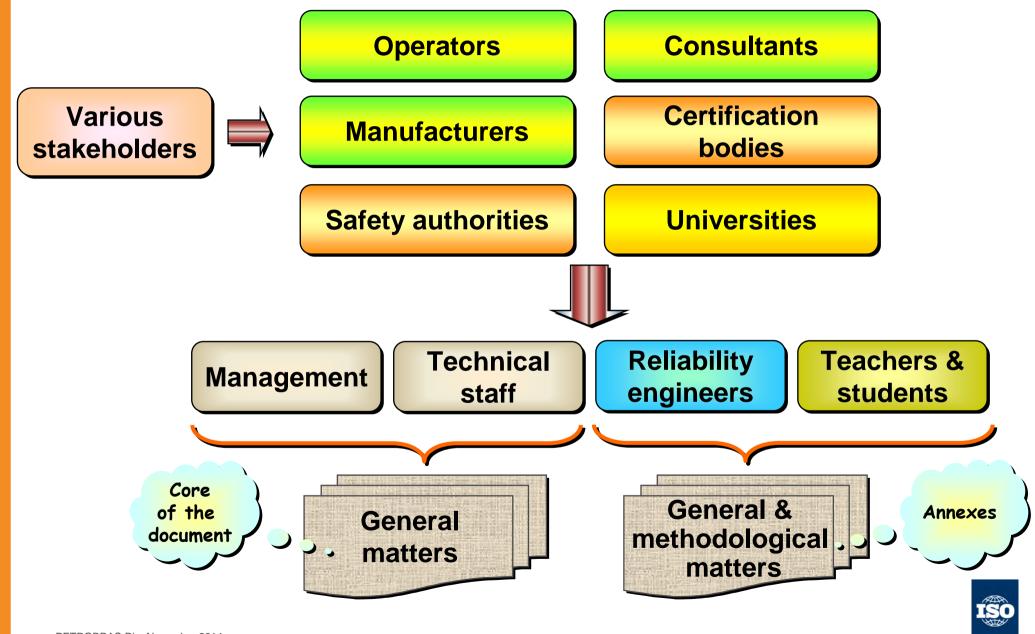


Overall framework of ISO/TR 12489

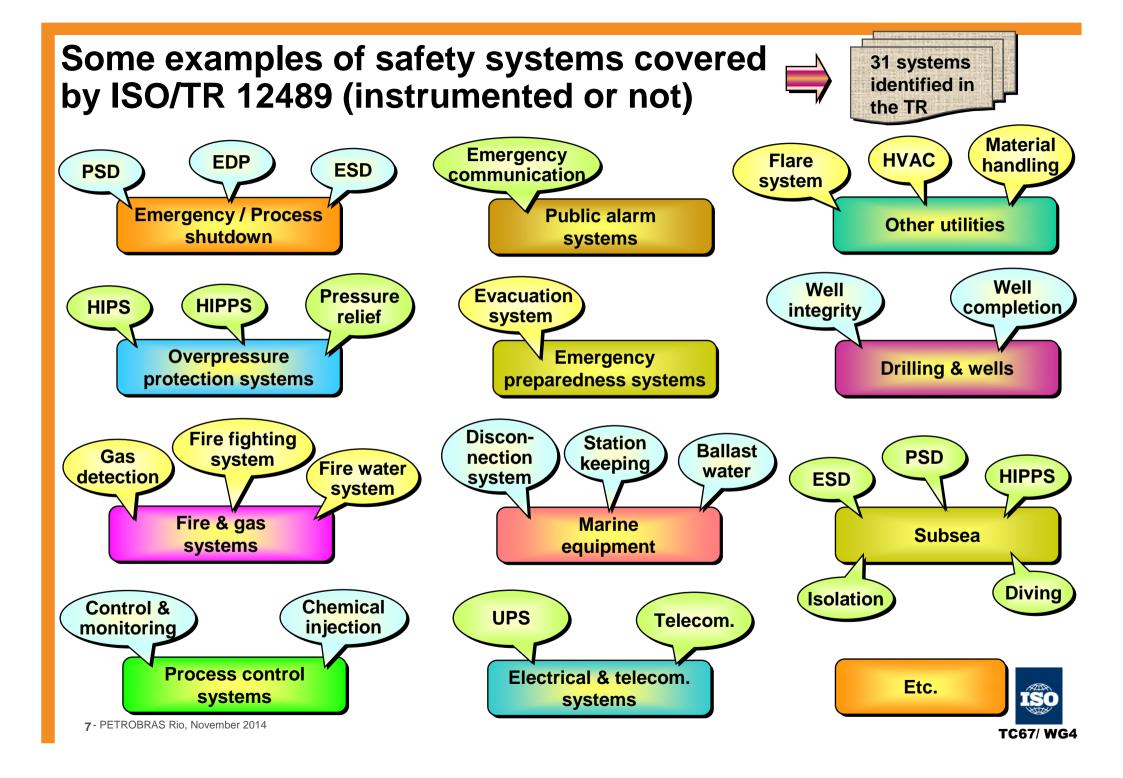
ISO 31000 Risk management With regards to: safety, environment, **Risk assessment** production, operations, Risk identification etc. **Risk analysis** Reliability analysis ISO/TR 12489 **Modelling** & calculations Risk evaluation

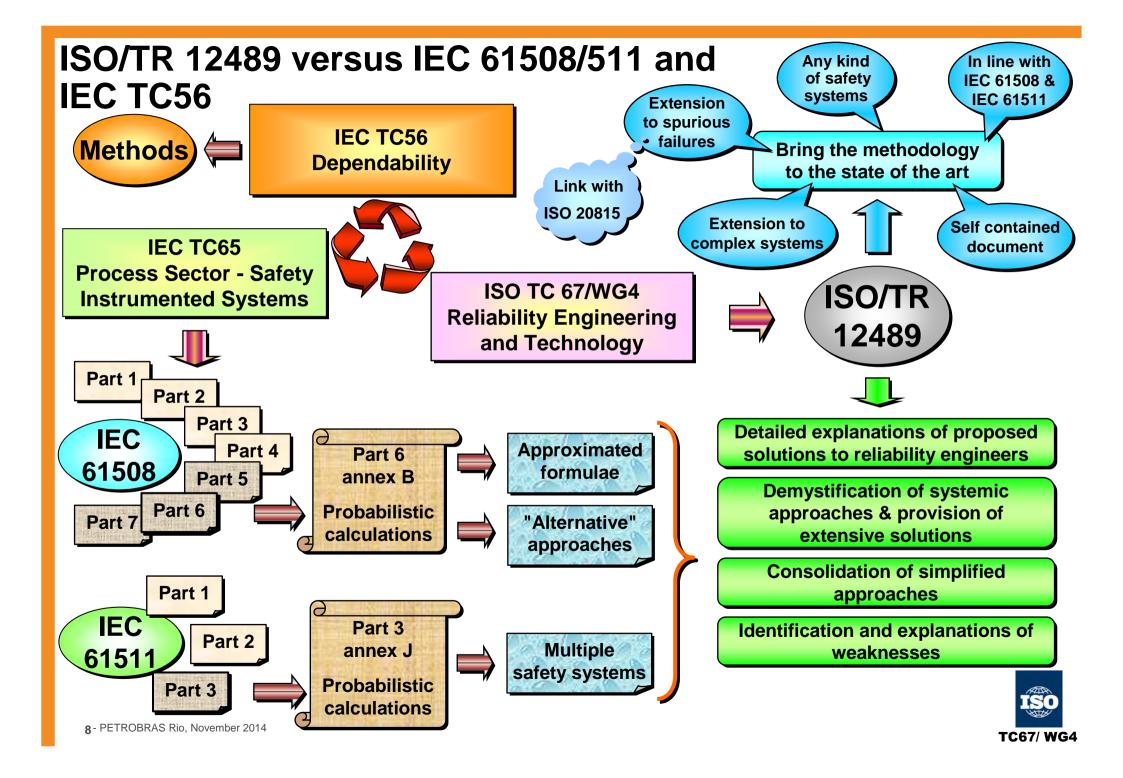


Target users of ISO/TR 12489



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Distribution of the topics within the 260 pages of ISO/TR 12489 Reliability data More than 30 Safety safety systems systems **Definitions** are identified 14% Uncertainty 34% **Monte Carlo** Overall General content General 8% matters **CCF** matters 41% Human 28% General factor analytics **21% Typical** applications Petri nets **Formula** 32% **6**% 26% **Miscellaneous** 30% **Approaches Approaches** 29% 26% Markov **Boolean**

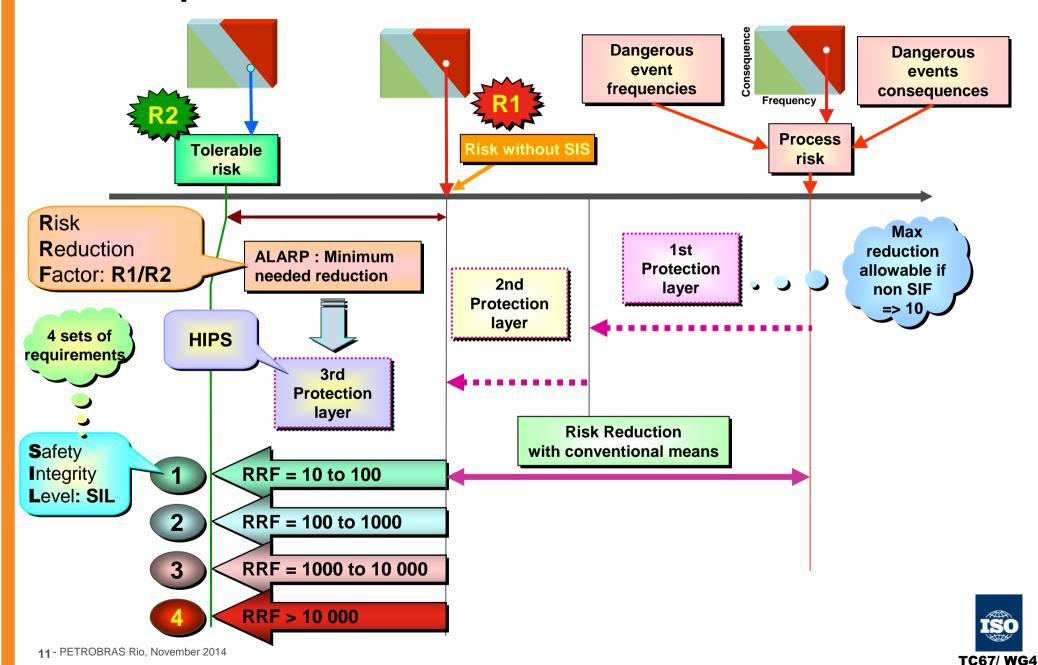
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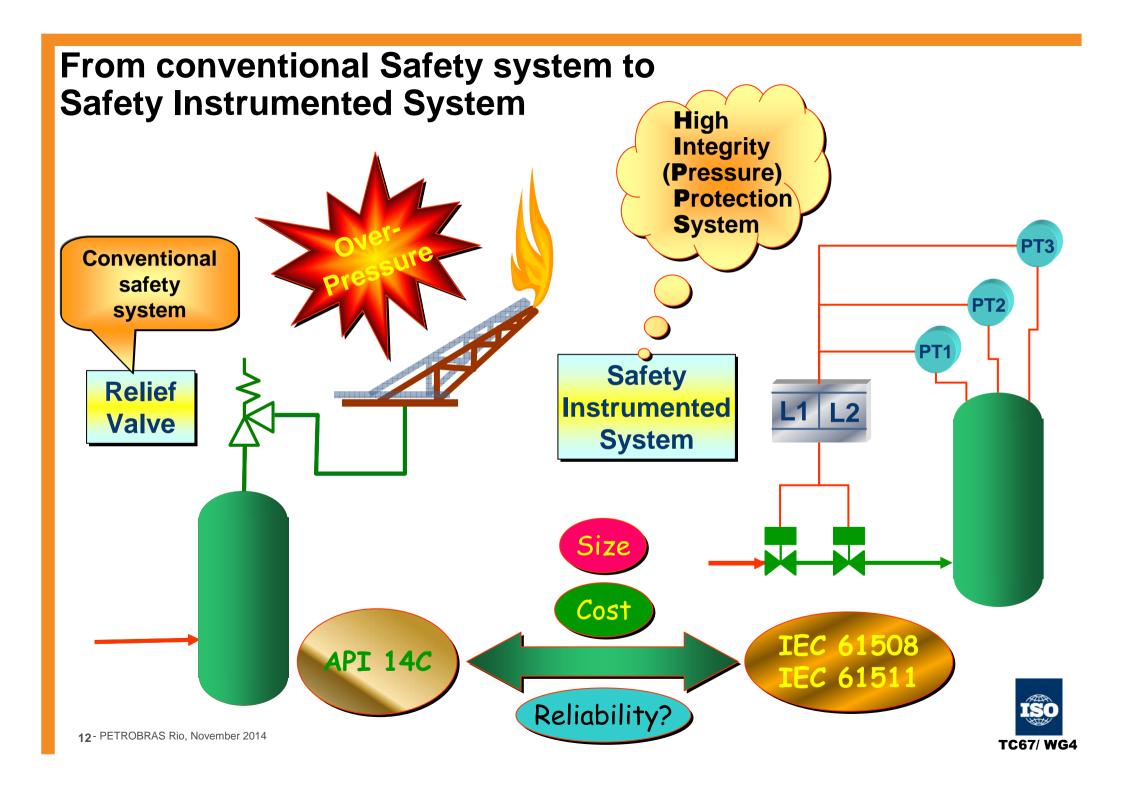
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Introduction to functional safety concepts

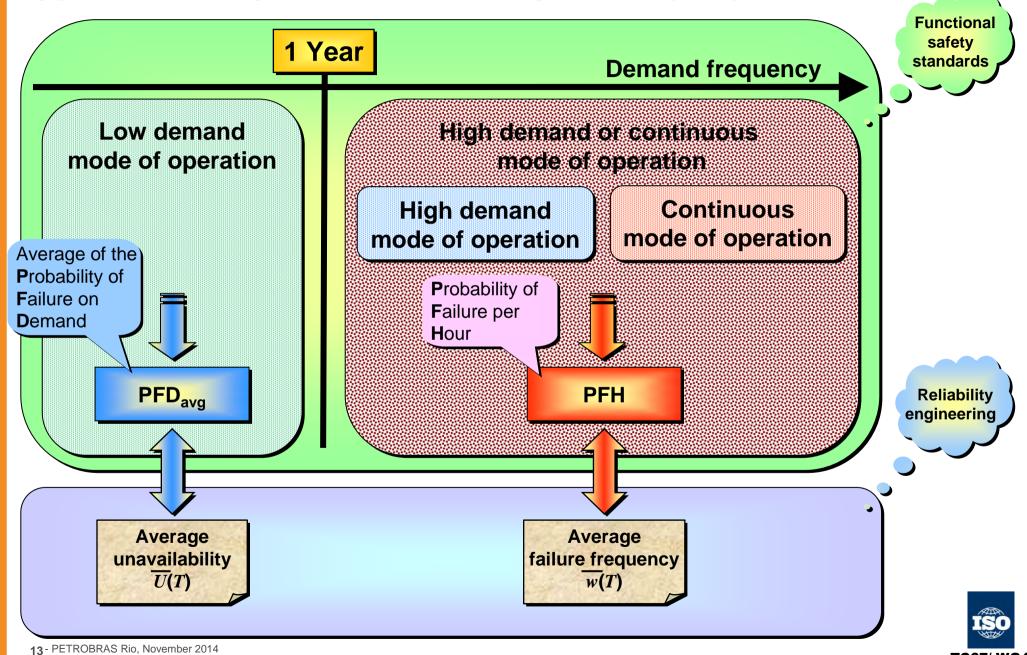


SIL Principle: identification of Risk Reduction needed

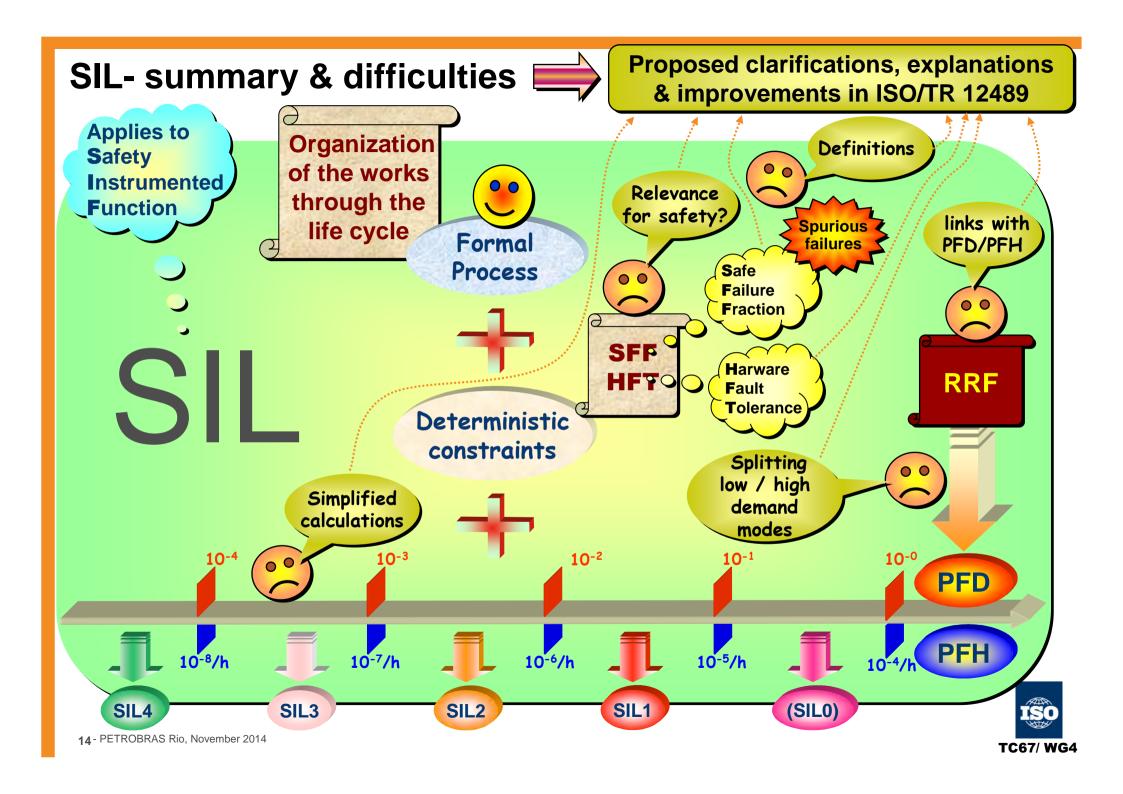




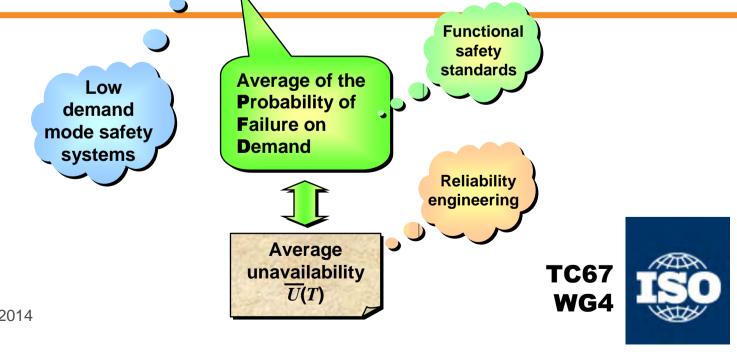
Types of Safety Instrumented Systems (SIS)

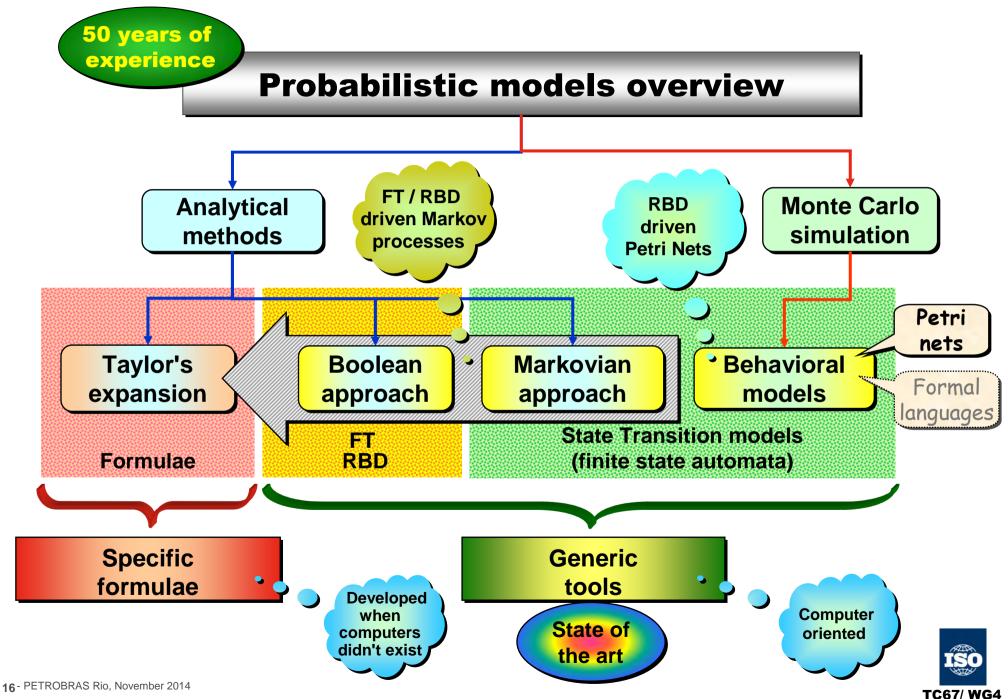


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Introduction to the methods developed into ISO/TR 12489 for PFD_{avg} calculations





Simplified analytical approach



Simplest approximation of the PFDavg



 $\tau << 1/\lambda$

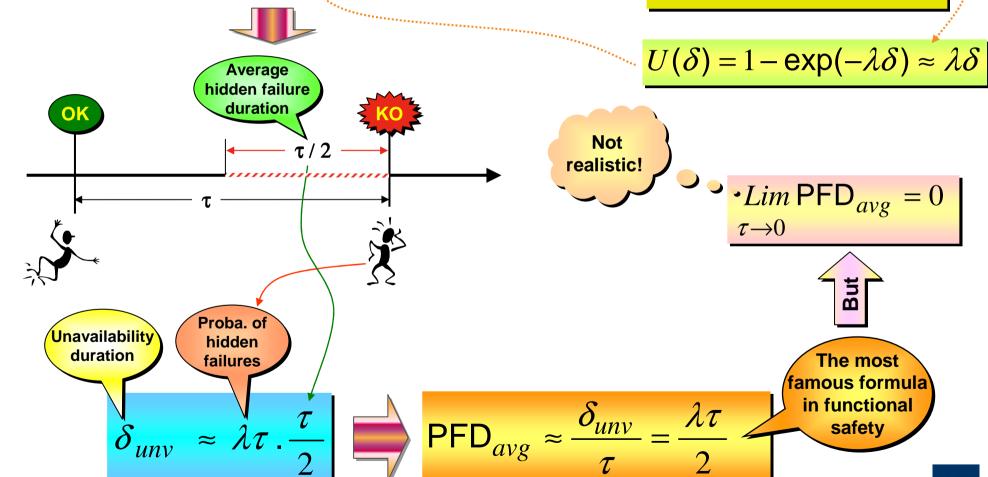
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$\mathsf{PFD}_{avg} = \overline{U}(\tau) \approx \frac{1}{\tau} \int_0^{\tau} \lambda \delta . d\delta = \frac{1}{\tau} \frac{\lambda \tau^2}{2} = \frac{\lambda \tau}{2}$

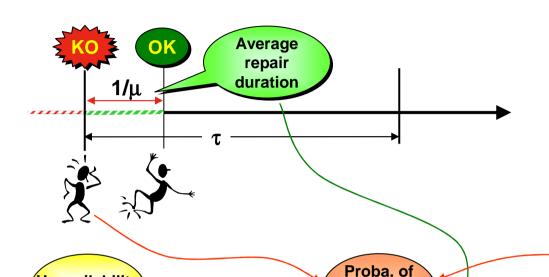
2 parameters:

 λ : Failure rate

τ : test interval



Approximation of the PFDavg from IEC 61508





 λ : Failure rate

τ : test interval

μ : repair rate

$$\tau - \frac{1}{\mu} \approx \tau$$

 $\tau << 1/\lambda$

 $1/\mu << \tau$

$$\delta_{unv} \approx \lambda \tau \cdot \frac{\tau}{2} + \lambda \tau \cdot \frac{1}{\mu}$$

hidden

failures

PFD
$$avg \approx \frac{\delta_{unv}}{\tau} = \frac{\lambda \tau}{2} + \frac{\lambda}{\mu}$$

IEC 61508 But

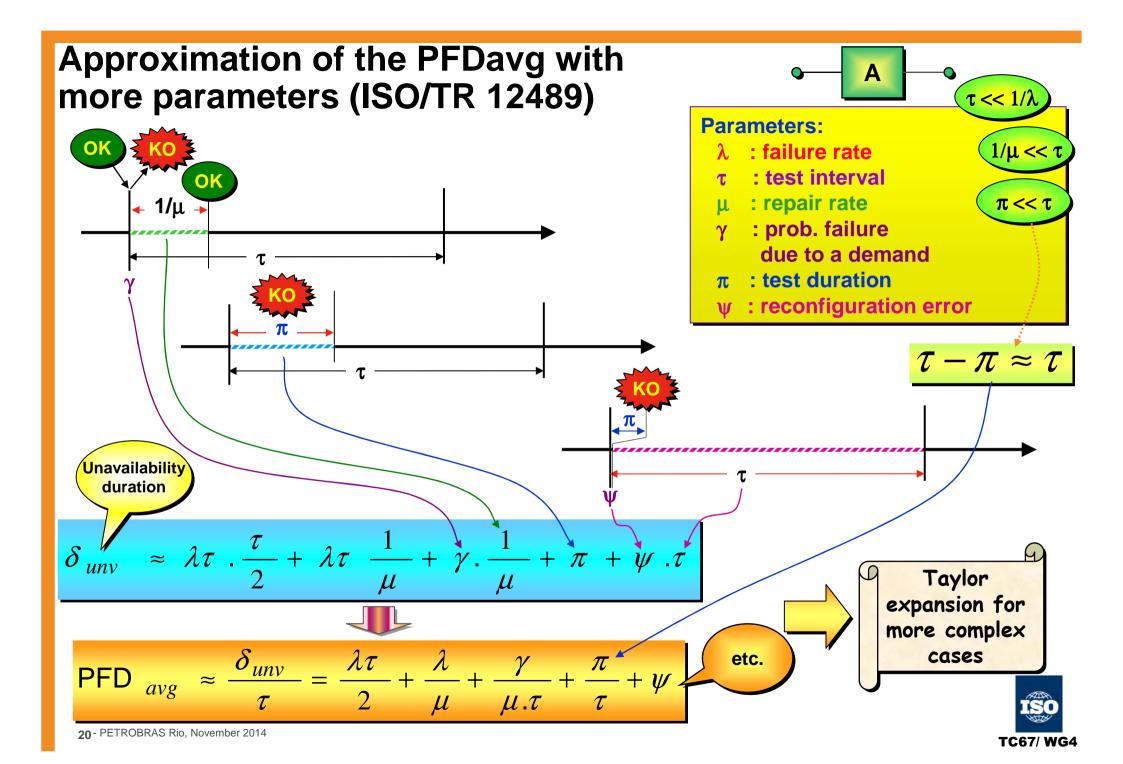
But parameters are missing





Unavailability

duration



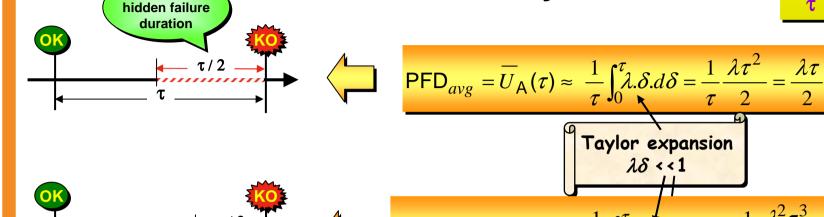
Limit average unavailability versus test interval **Parameters:** λ: failure rate : test interval Average unavailability $\overline{U} = PFD_{avg}$: repair rate : prob. failure due to a demand Not enough **Too much** tests tests vincreases log-log graphic Two test intervals for the same Flat in the Test interval auvicinity of the minimum \mathcal{T}_2 **Need for** Optimum data collection to estimate 21 - PETROBRAS Rio, November 2014 TC67/ WG4

Simplest approximation of the PFDavg for redundant systems Average

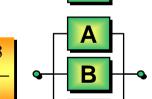
2 parameters:

: Failure rate

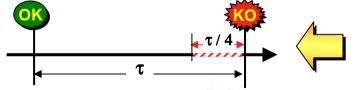
: test interval



$$\mathsf{PFD}_{avg} = \overline{U}_{\mathsf{AB}}(\tau) \approx \frac{1}{\tau} \int_0^\tau (\lambda.\delta)^2 d\delta = \frac{1}{\tau} \frac{\lambda^2 \tau^3}{3} = \frac{(\lambda \tau)^2}{3}$$



 $\tau << 1/2$



$$\mathsf{PFD}_{avg} = \overline{U}_{\mathsf{ABC}}(\tau) \approx \frac{1}{\tau} \int_0^{\tau} (\lambda \cdot \delta)^3 d\delta = \frac{1}{\tau} \frac{\lambda^3 \tau^4}{4} = \frac{(\lambda \tau)^3}{4}$$



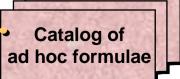
Not possible to combine formulae!

 $U_{AB}(\tau) \neq U_{A}(\tau).U_{B}(\tau), \quad U_{ABC}(\tau) \neq U_{A}(\tau).U_{B}(\tau).U_{C}(\tau)$

Effect of systemic

dependencies

Not in line with reliability analysis philosophy



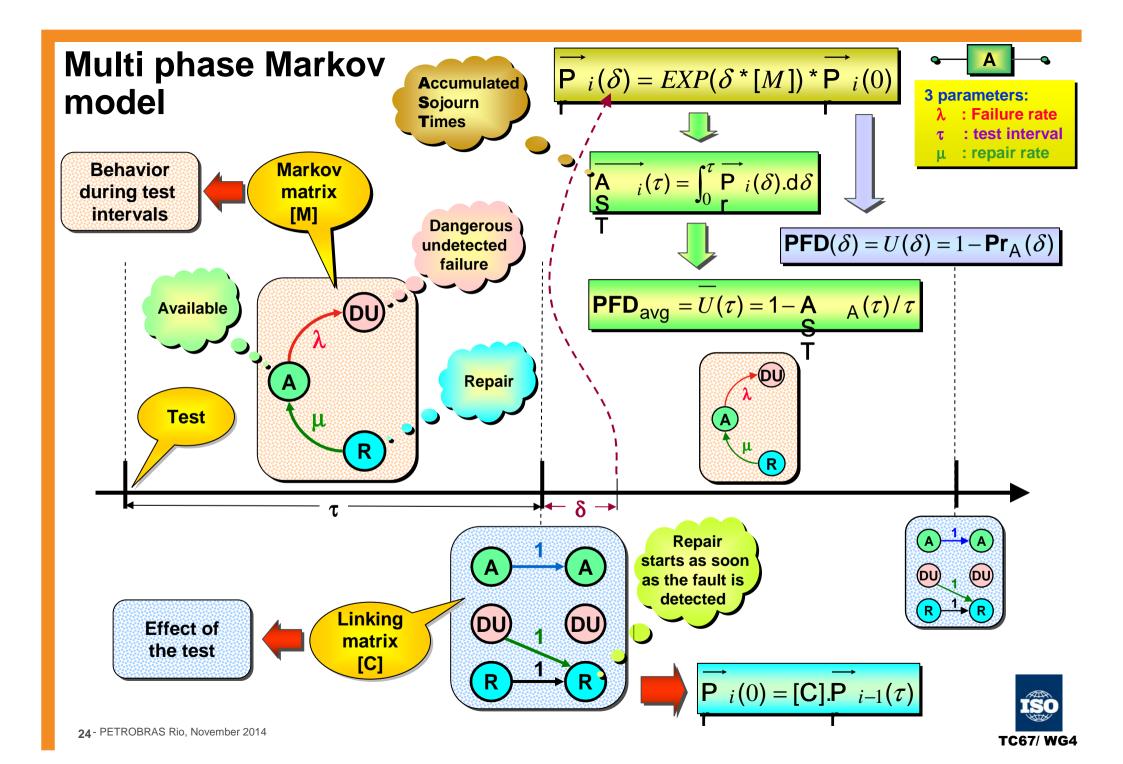
Even for simplest systems, each case implies specific **Taylor expansion development**



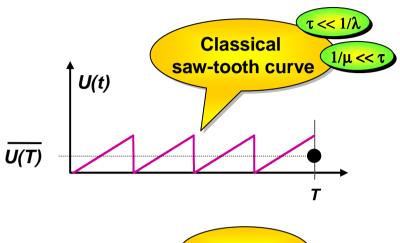
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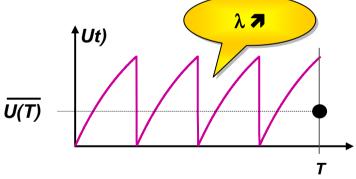
Multi-phase Markovian approach

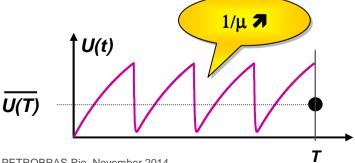




Typical saw-tooth curves for a single periodically tested component









Parameters:

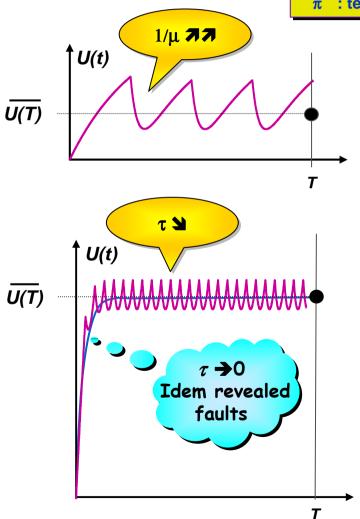
 λ : failure rate

τ : test interval

μ : repair rate

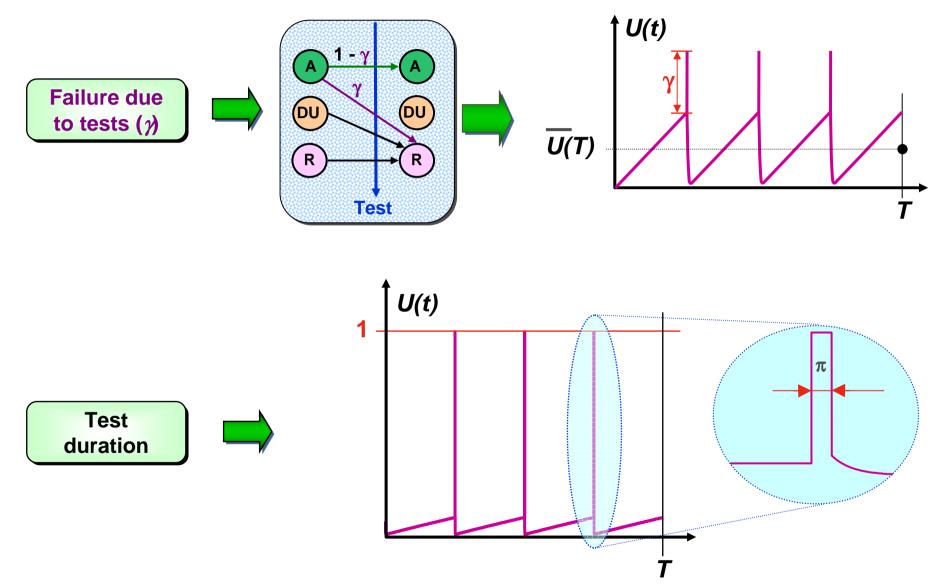
: prob. failure due to a demand

 π : test duration





Modeling the probability of failure due to the demand itself and the test duration

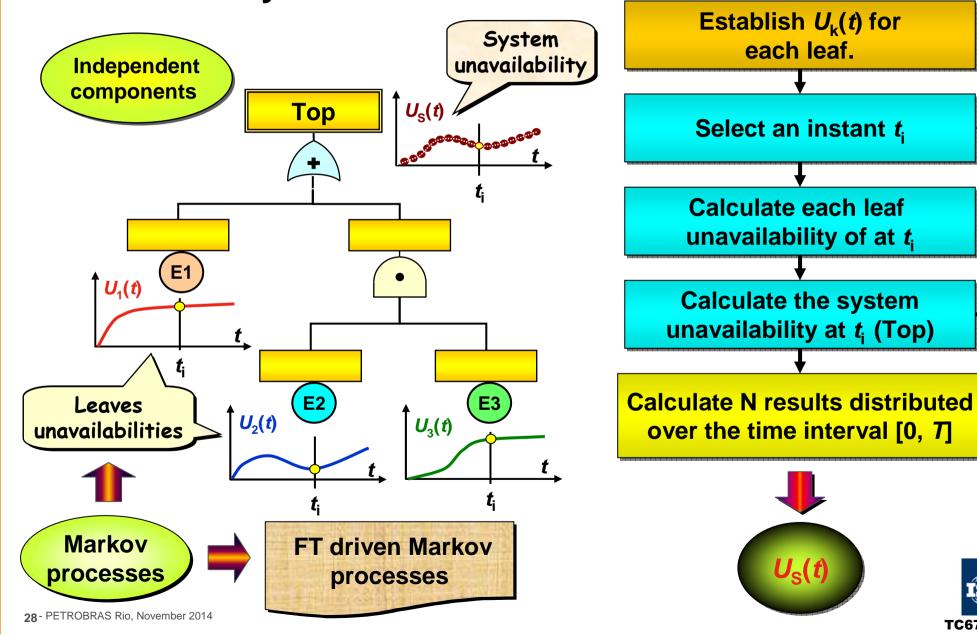




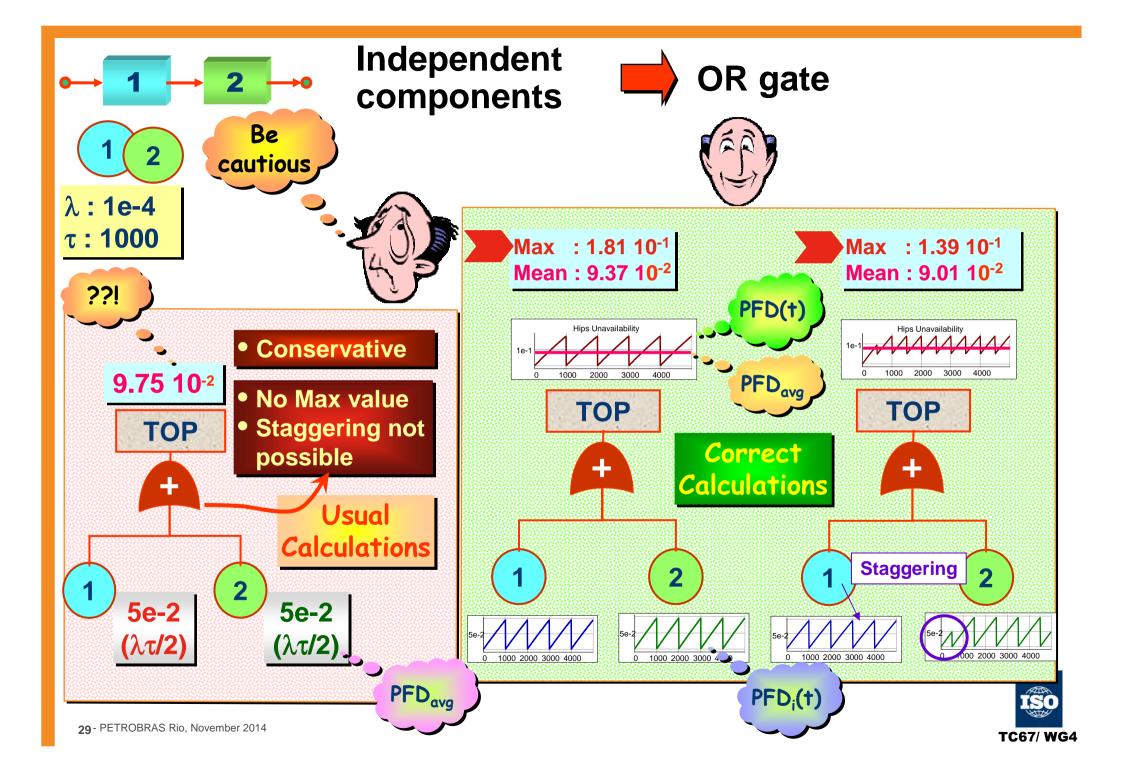
Fault tree approach

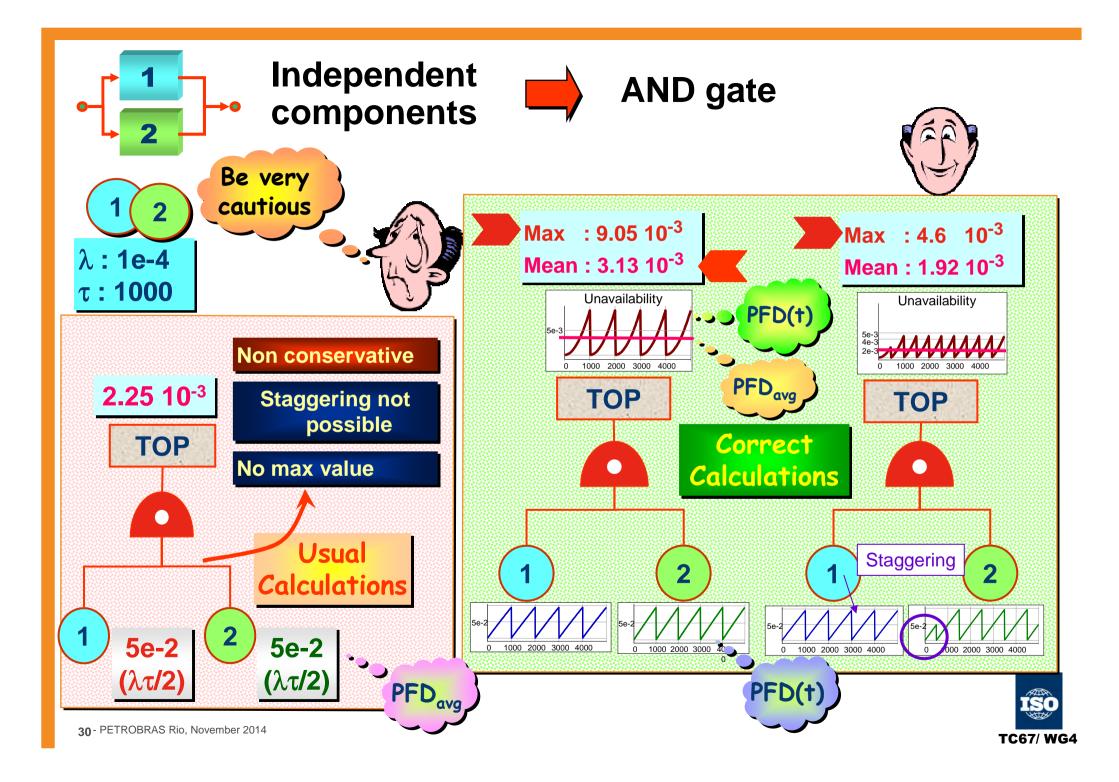


Fault tree driven Markov processes: principle for unavailability calculation.

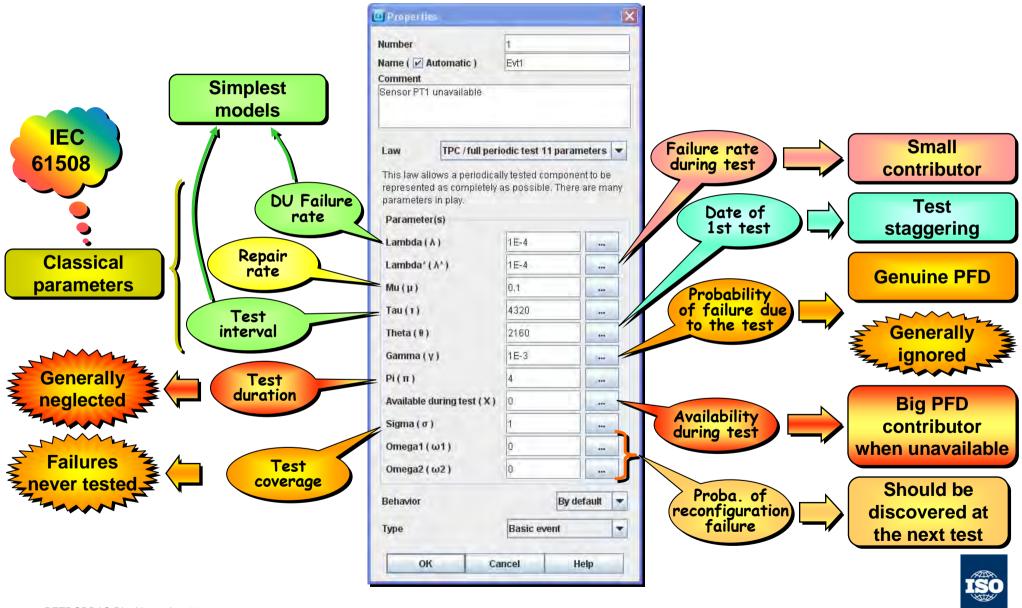


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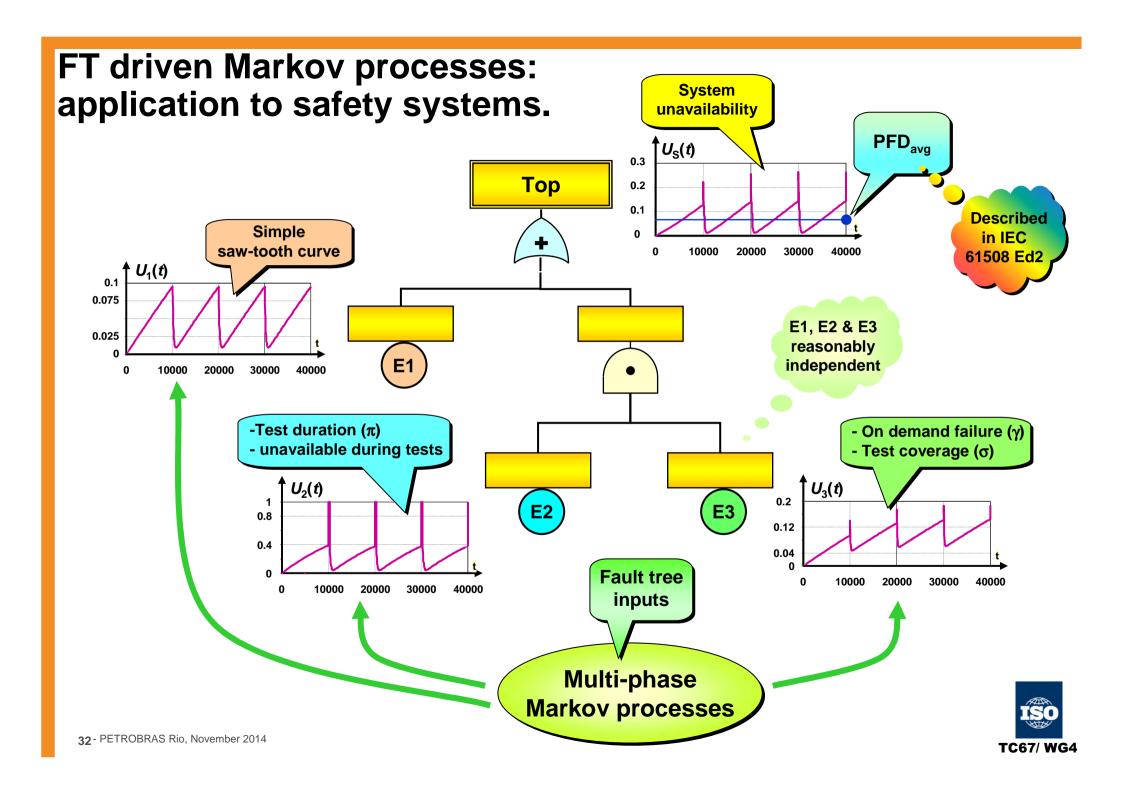




Parameters of a periodically tested component (dangerous undetected failures)



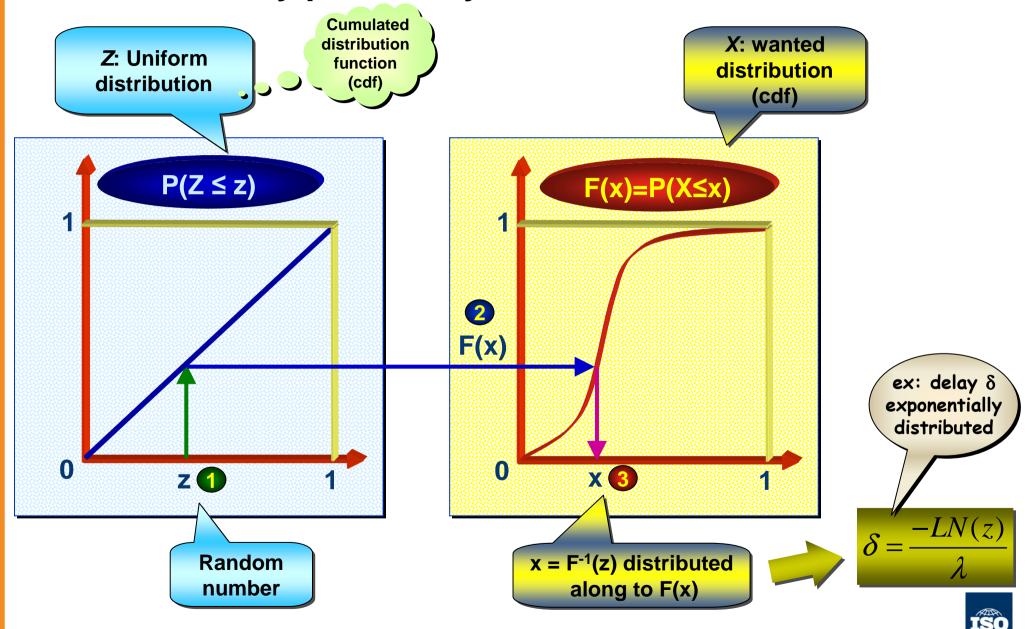
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RBD driven Petri net and Monte Carlo simulation approaches



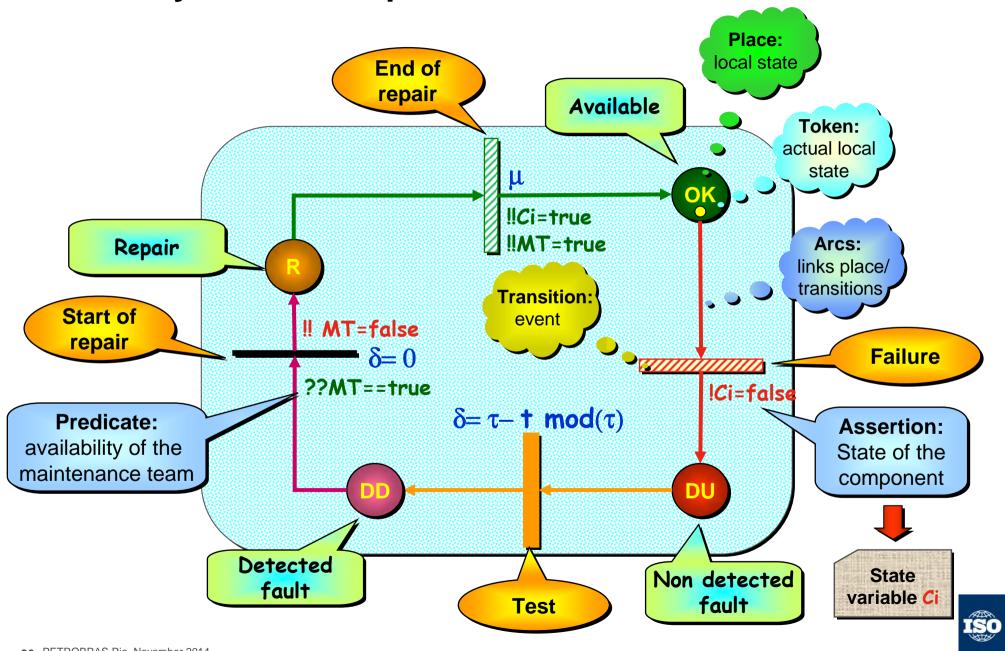
Simulation of any probability law



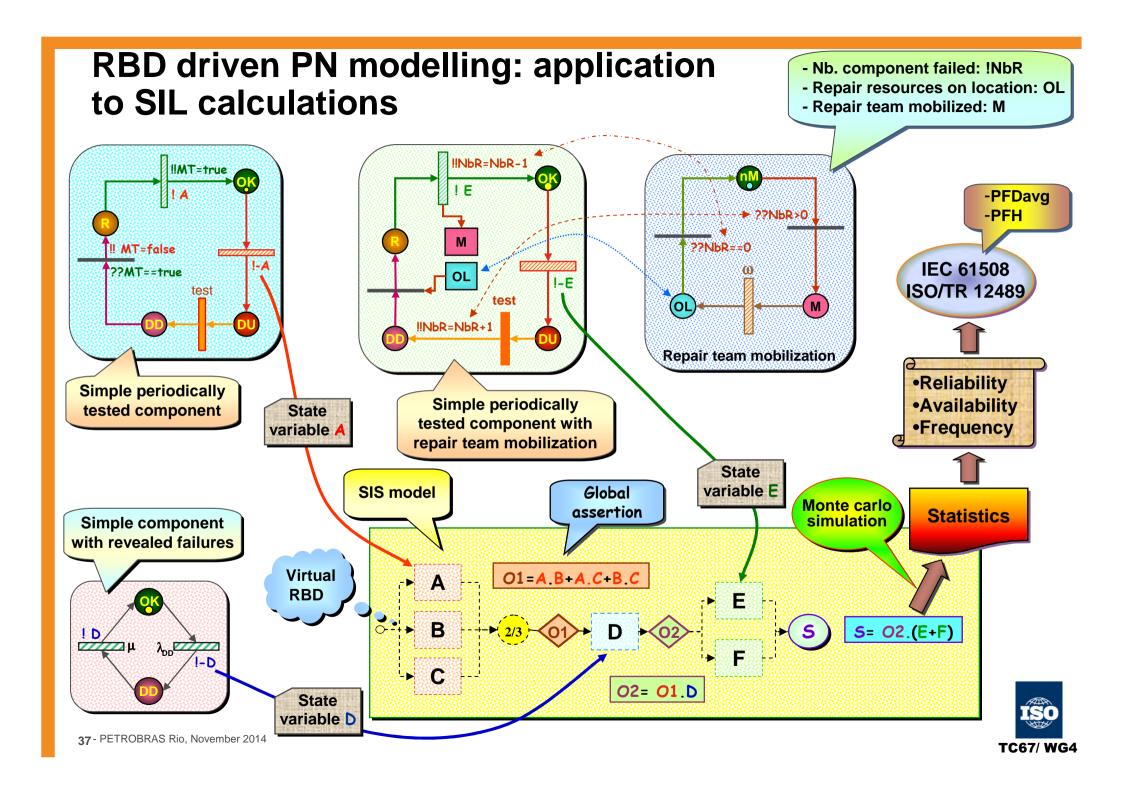
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Random number generators **Thermal** noise Zener diode **Physical** methods Several billons are known 3,14159265358979323846264338327950288419716939937510 Decimals of π 58209749445923078164062862089986280348253421170679 82148086513282306647093844609550582231725359408128 Widely used Linear J. Von Neumann congruential generators Pseudo random $X_{n+1} = (a.X_n + b) \mod m$ Computer number generators Length of **Trajectory** of the boule one revolution

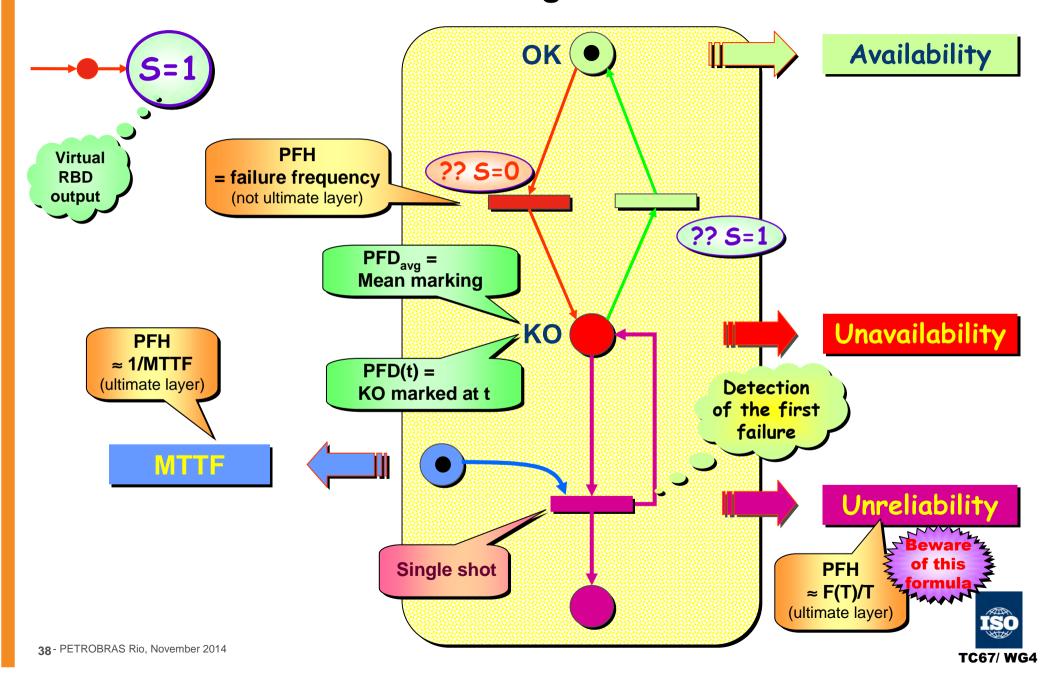
Periodically tested component

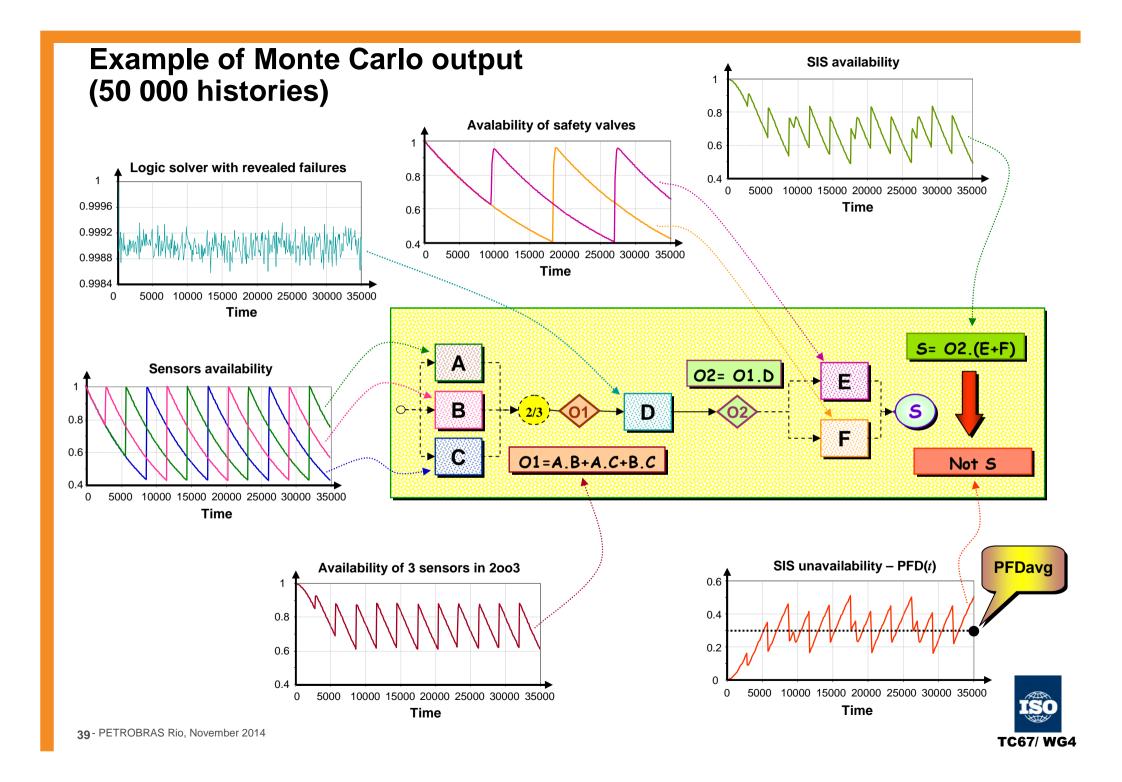


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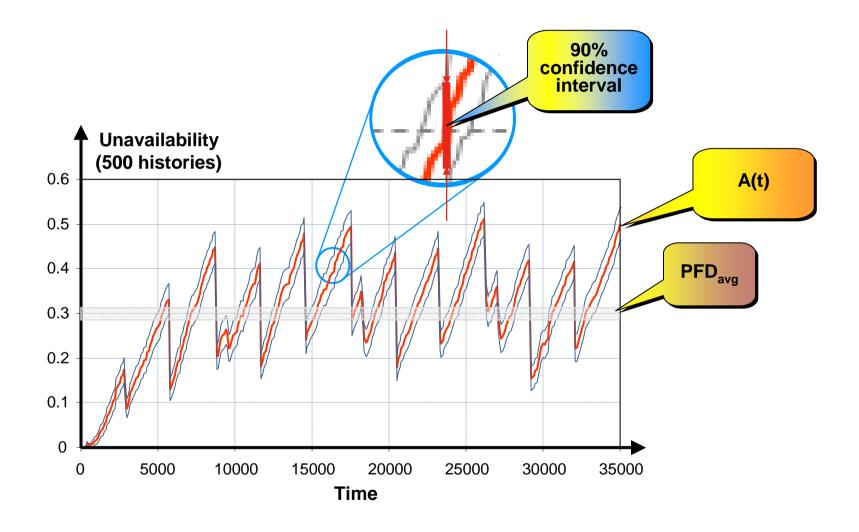


Parameter calculations: The magic sub PN!



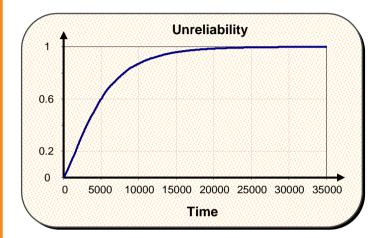


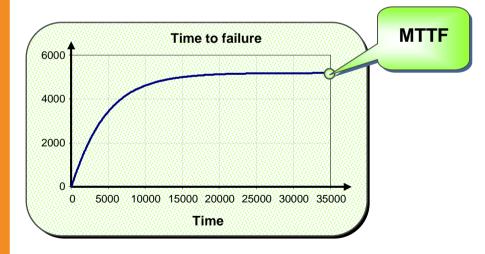
Monte Carlo simulation uncertainties

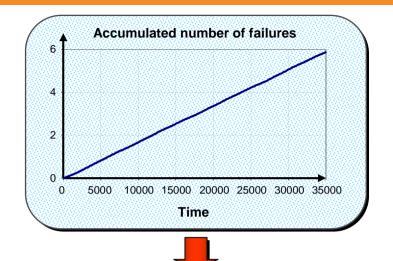


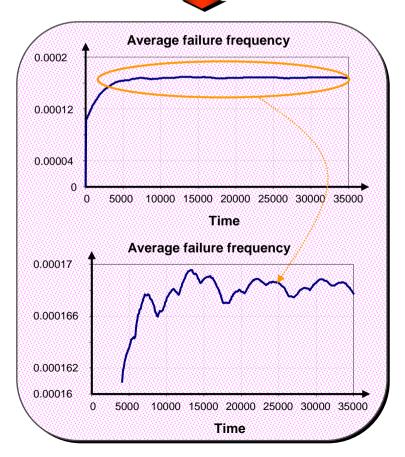


Other possible outputs







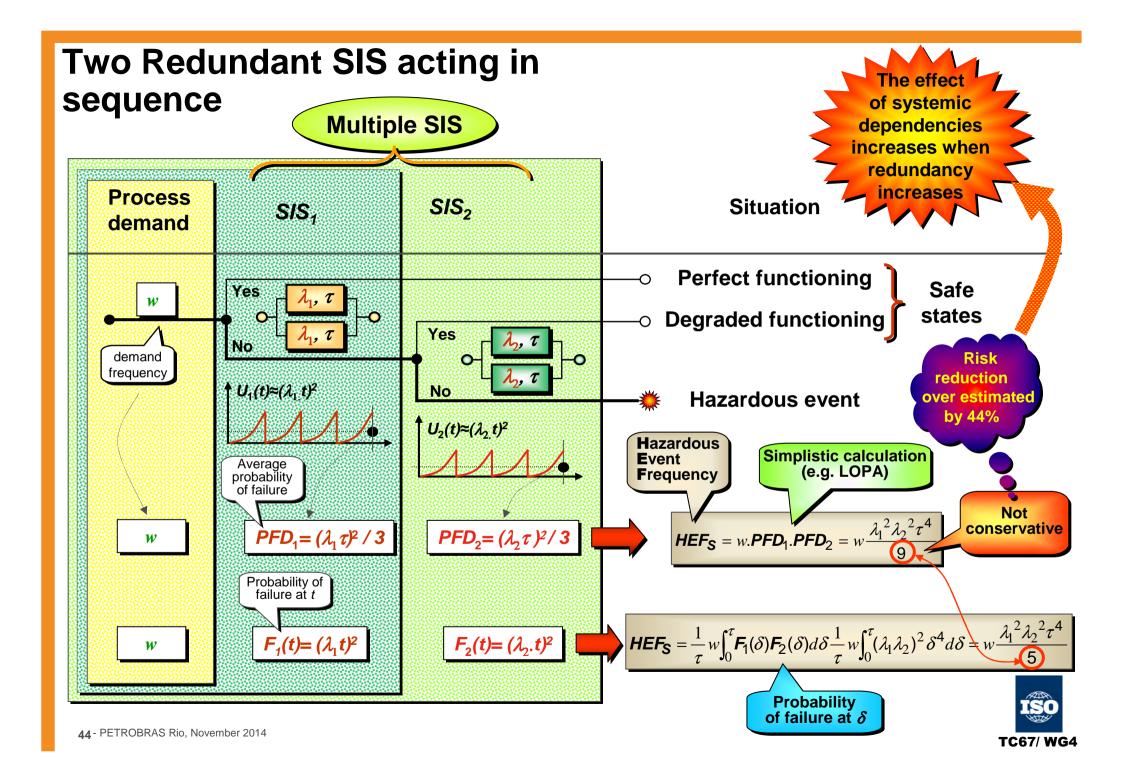




Multiple safety systems



Two simple SIS acting in sequence **Effect due Multiple SIS** to systemic dependencies **Process** SIS, **Situation** SIS demand **Perfect functioning** Safe Yes states **Degraded functioning** Yes No Risk demand frequency reduction No **Hazardous event** $U_1(t) \approx \lambda_1 t$ over estimated by 25% U₂(t)≈λ₂t **H**azardous Simplistic calculation Event Average probability (e.g. LOPA) Frequency of failure Not $HEF_S = w.PFD_1.PFD_2 = w \frac{\lambda_1 \lambda_2 \tau^2}{2}$ conservative $PFD_1 = \lambda_1 \tau / 2$ $PFD_2 = \lambda_2 \tau / 2$ Probability of failure at *t* $HEF_{S} = \frac{1}{\tau} w \int_{0}^{\tau} F_{1}(\delta) F_{2}(\delta) d\delta \frac{1}{\tau} w \int_{0}^{\tau} \lambda_{1} \lambda_{2} \delta^{2} d\delta = w \frac{\lambda_{1} \lambda_{2} \tau^{2}}{3}$ $F_2(t) = \lambda_2.t$ $F_1(t) = \lambda_1 t$ **Probability** of failure at δ 43 - PETROBRAS Rio, November 2014 TC67/ WG4



Event tree (multiple SIS) or fault tree (redundant SIS) calculation difficulties



Explained in IEC 61511 and ISO/TR 12489

